

<b>FORM PTO-1449 U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE</b>  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use several sheets if necessary)		<b>ATTY. DOCKET NO.</b>		<b>SERIAL NO.</b>			
		<b>U 016442-2</b>					
		<b>APPLICANT</b>					
		<b>Satoru TANAKA et al.</b>					
		<b>FILING DATE</b>		<b>GROUP</b>			
<b>U.S. PATENT DOCUMENTS</b>							
<b>EXAMINER INITIALS</b>	<b>REFERENCE DESIGNATION</b>	<b>DOCUMENT NUMBER</b>	<b>DATE</b>	<b>NAME</b>	<b>FILING DATE IF APPROPRIATE</b>		
	AA	2003/0018918	01/2003	Natsuno et al.			
	AB						
	AC						
	AD						
	AE						
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	AG						
	AH						
	AI						
	AJ						
	AK						
<b>FOREIGN PATENT DOCUMENTS</b>							
		<b>DOCUMENT NUMBER</b>	<b>DATE</b>	<b>COUNTRY</b>	<b>TRANSLATION</b> <table border="1" style="width: 100%; border-collapse: collapse;"> <tr> <td style="width: 50%;"><b>YES</b></td> <td style="width: 50%;"><b>NO</b></td> </tr> </table>	<b>YES</b>	<b>NO</b>
<b>YES</b>	<b>NO</b>						
	AL	2003-258856	09/2003	JP		X	
	AM	2003-85084	03/2003	JP		X	
	AN	2001-209611	08/2001	JP		X	
	AO	02/39294	05/2002	WO		X	
	AP						
<b>OTHER ART (Including Author, Title, Date, Pertinent Dates, Etc.)</b>							
	AQ	Patent Abstracts of Japan of 2003-258856 dated September 12, 2003					
	AR	Patent Abstracts of Japan of 2003-85084 dated March 20, 2003					
	AS	Patent Abstracts of Japan of 2001-209611 dated August 3, 2001					
<b>EXAMINER</b> /Michael Vaughan/			<b>DATE CONSIDERED</b> 09/30/2008				
<b>EXAMINER:</b> Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							